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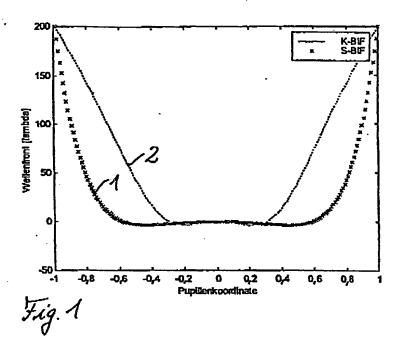
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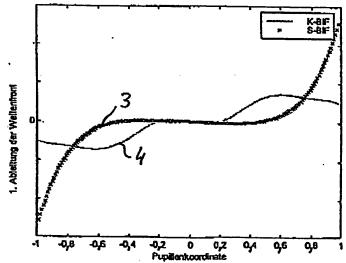
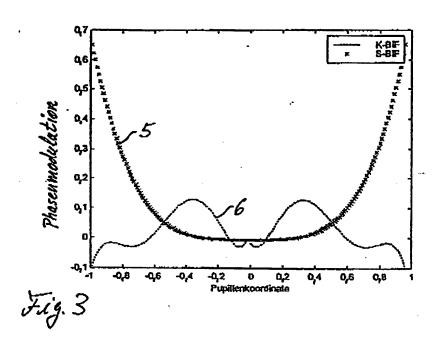
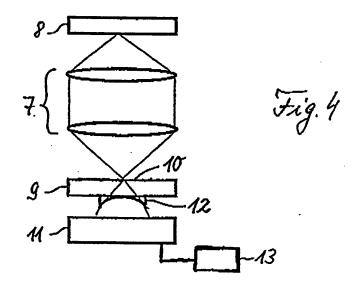


Fig. 2

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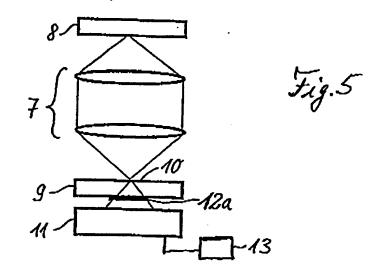
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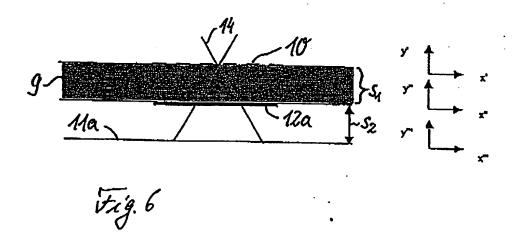




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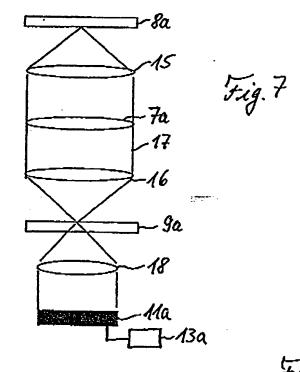
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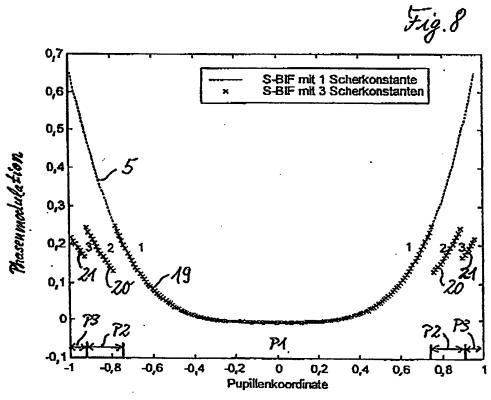




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Fig. g

